

Search Notes

Application/Control No.

10/053,585

Examiner

Christopher L. Chin

Applicant(s)/Patent under
Reexamination

NAYA ET AL.

Art Unit

1641

SEARCHED

Class	Subclass	Date	Examiner
Updated	search	7/10/2006	CC

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR